

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE**INFORMATION DISCLOSURE
STATEMENT**Docket Number:
10191/3964Application Number
To be assignedFiling Date
HerewithExaminer
To be assignedArt Unit
To be assignedInvention Title
**PLASMA SYSTEM AND METHOD FOR
ANISOTROPICALLY ETCHING
STRUCTURES INTO A SUBSTRATE**Inventor(s)
LAERMER, Franz et al.

Address to:

Mail Stop PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant hereby brings the following references to the attention of the Examiner. The references are listed on the attached modified PTO Form No. 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of the patents listed on the modified PTO form 1449 are enclosed, unless otherwise indicated.

Dated:

4/7/05

By:

Richard L. Mayer, Reg. No. 22,490

KENYON & KENYON
One Broadway
New York, New York 10004
(212) 425-7200 (telephone)
(212) 425-5288 (facsimile)

INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO-1449	DOCKET NO. 10191/3964	CLASS NO. 10/530612 To be assigned
	APPLICANT LAERMER, Franz et al.	
	FILING DATE To be assigned	GROUP To be assigned

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT/PUBLICATION NUMBER	PATENT/PUBLICATION DATE	NAME	CLASS	SUBCLASS	FILING DATE
	** 6,431,113	August 13, 2002	PUECH, Michel			
	** 2002/144974	October 10, 2002	LAERMER, Franz et al.			
	2002/0000422	January 3, 2002	DONOHUE et al.			
	2002/0148807	October 17, 2002	ZHAO et al.			
	6,071,822	June 6, 2000	DONOHUE et al.			
	5,498,312	March 12, 1996	LAERMER et al.			

** Copy of reference not provided since the reference is cited in the International Search Report (copy provided by the International Search Authority).

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						Yes	No
	42 41 045	May 26, 1994	Germany			X** - Abstract	
	100 51 831	May 2, 2002	Germany			X** - Abstract	
	WO 00/79579	December 28, 2000	PCT				X**
	199 33 841	February 1, 2001	Germany				X**
	0 849 766	June 21, 1998	EPO				X**
	198 26 382	February 7, 2002	Germany				
	197 06 682	August 27, 1998	Germany				
	197 36 370	March 4, 1999	Germany				
	199 27 806	January 4, 2001	Germany				
	199 33 842	February 1, 2001	Germany				

* Mentioned in Specification.

** Copy of reference not provided since the reference is cited in the International Search Report (copy provided by the International Search Authority).

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	